

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 09/944,332 SHEN ET AL.	
		Examiner	Art Unit Qi Han	2626 Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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